DEPARTMENT OF MATERIALS SCIENCE AND ENGINEERING

DOE-NSF-ONR-AFOSR





Image Processing in Expts. + Simulations of Plastic Deformation of Polycrystals ICIP 2014, Paris

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Why understand plastic deformation?

We need to understand plastic deformation down to the scale of individual grains because the extreme values of stress, strain and orientation gradients control many phenomena.

Orientation map of shocked copper



Cerreta, Fensin, Lieberman ...

E.g. Hot spots in normal tractions (plus other components) generate voids:



Voids are easy to find by thresholding a CT image, except when they approach the resolution limit! E.g. hot spots in orientation gradients nucleate recrystallization



Wang, Acta mater. **59** 3872 (2011) 2

High Energy X-ray Diffraction Microscopy (nf-HEDM)

Advanced Photon Source Measurements

- 1-ID high brilliance, high energy x-rays
- Millimeter samples probed with micron spatial, < 0.1 deg orientation resolution
- Tera-byte data sets
- $> 3 \times 10^6$ Bragg peaks
- 10³ core parallel processing: 2D images to 3D orientation maps

3D copper microstructure



 0.4 mm^3

 $\mathbf{x}_{d} = \mathbf{L}$

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Sample grid

Stack of layers = 3D microstructure Colors based on crystal orientations

HEDM measurement schematic



Image diffracted beams

- 360 images/layer
- ~100 successive cross-

Poulsen, Springer 2004 Suter et al., Rev. Sci. Instruments, 2006

Li and Suter, J Appl. Cryst. 2013; LLNL-CODE-657639

Reconstruction via Forward Modeling

Optimizes orientations in > 10^7 voxels (volume elements)



Image Refinement

- Previous : Simple threshold (baseline + ratio)
- Risk of peak overlap, esp. strong adjacent to weak, esp. smeared peaks from plastic strain.
- Added Laplacian of Gaussian (LoG) filter
- Use Δ [Im] == 0 (crossing points) to define peak extent
- Current : Previous with low baseline + local intensity variation edge detection
- Will further segment merged peaks
- Sensitive to internal peak variations (twins)
- Improved peak segmentation aids Forward Modeling Method because larger fraction of peaks fitted
- References: Jonathan Lind, PhD thesis in Physics, Carnegie Mellon University (2013); "Tensile twin nucleation events coupled to neighboring slip observed in three dimensions", J. Lind *et al.* Acta mater. (2013) **74** 213-220.

Segmentation of Peaks

- Previous : Simple threshold (baseline + ratio)
- Added Laplacian of Gaussian (LoG) filter
- Use Δ [Im] == 0 to define peak extent



Diffractogram example



Segmentation: Original vs. LoG

Baseline levels of 5 (left), 10 (center) and 20 (right hand column) Unique color indicates segmented peak: longer series \Rightarrow improved segmentation



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Old method (threshold)



Old method (threshold)



New Method (LoG)



LoG – Quality map



Compare Old vs LoG methods



HEDM of Tensile Test on Zr

 Initial goal was to correlate void formation with microstructural features



 $\{10\bar{1}0\}$

(0001)



Schmid factors, Resolved Shear Stress



Schmid factors at 0 % - Schmid factors at 13 % - Resolved Shear Stress

- Each line = an observed twin
- Green zone: positive Schmid factors
- Red zone: negative Schmid factors
- Set of 6 marks indicates the variants; white mark = observed twin variant
- Full field elastic stress calculation provides resolved shear stresses; little change compared to simple Schmid factors
- Several variants occur with negative Schmid factors \Rightarrow Plasticity influences twinning

(Anisotropic) elastic stress-strain fields computed with FFT method

Other Image Challenges



The striations are "**slip bands**" i.e. concentrated surface displacement from dislocation motion: how best to quantify such features?

Deformed metal reveals a grain structure but the **boundaries** (white lines) are incomplete: how to complete the network?

One complete crystallite (grain) visible. Many platy (anisotropic) precipitates (2nd phase **particles**) visible. How to segment and measure the particles?

Software ...

Many of the algorithms that we use to analyze 3D microstructures are available in Dream3D (open source, Mac/PC/Linux); also ITK.



Summary

- The Forward Modeling Method for indexing diffractograms from x-ray diffraction experiments at synchrotrons depends on identifying peaks. Simple thresholding works for well annealed samples and isotropic intensity peaks. For smeared anisotropic peaks from plastically deformed materials, the Laplacian-of-Gaussians works significantly better.
- Comparisons do not show good agreement between experiment and simulation; statistical comparisons look reasonable (e.g. texture development, orientation gradients).
- A tensile test on Zr showed several twinning events, despite unfavorable texture. Some twins appeared in grains with negative Schmid factor. Links to slip activity also evident.
- Recent review of literature suggests that lack of agreement is the general result (with no known exceptions).
- Orientations and orientation gradients evaluated in a Cu specimen; compared with vpFFT simulation.
- KAM is higher near to grain boundaries; correlated with gradients in stress.

Prospects

- Direct comparison with diffraction data sets
- We need maps of the elastic strain tensor
- Simulations that include finite strain
- Test various concepts such as latent hardening, strain gradient etc.
- Model polycrystal problems with dislocation dynamics
- Use better constitutive descriptions



Stress from dislocation loops, calculated with FFT method.